

Single N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

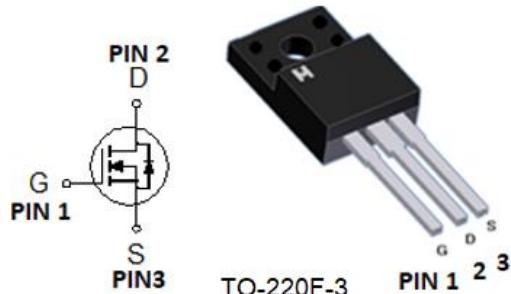
BV _{DSS}	100V
R _{DSON} (MAX.)	25mΩ
I _D	50A

Single N Channel MOSFET

UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free

Pin Description:



ABSOLUTE MAXIMUM RATINGS (T_c = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±30	V
Continuous Drain Current	T _c = 25 °C	I _D	50	A
	T _c = 100 °C		35	
Pulsed Drain Current ¹		I _{DM}	150	
Avalanche Current		I _{AS}	30	
Avalanche Energy	L = 0.1mH, ID=30A, RG=25 Ω	E _{AS}	45	mJ
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	22.5	
Power Dissipation	T _c = 25 °C	P _D	128	W
	T _c = 100 °C		50	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	0.97	62.5	°C / W
Junction-to-Ambient	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³Pulsed drain current rating is package limited.

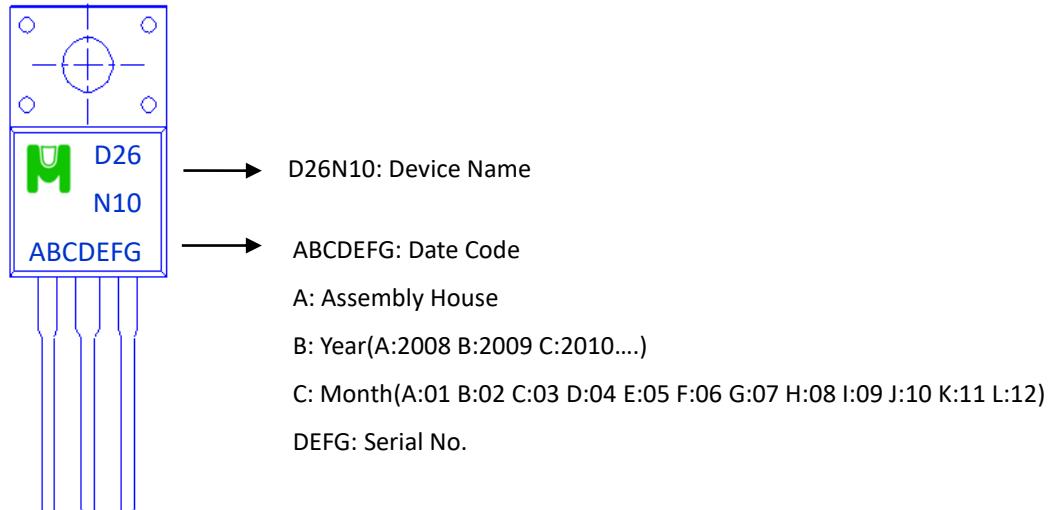
ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2.0	3.0	4.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 70\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	50			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 30\text{A}$		21.5	25	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 30\text{A}$		38		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		1575		pF
Output Capacitance	C_{oss}			216		
Reverse Transfer Capacitance	C_{rss}			47		
Gate Resistance	R_g	$V_{\text{GS}} = 15\text{mV}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.5		Ω
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 30\text{A}$		20.8		nC
Gate-Source Charge ^{1,2}	Q_{gs}			8.5		
Gate-Drain Charge ^{1,2}	Q_{gd}			6.8		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 50\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		20		nS
Rise Time ^{1,2}	t_r			80		
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			90		
Fall Time ^{1,2}	t_f			100		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S				50	A
Pulsed Current ³	I_{SM}				150	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 25\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		120		nS
Reverse Recovery Charge	Q_{rr}			380		nC

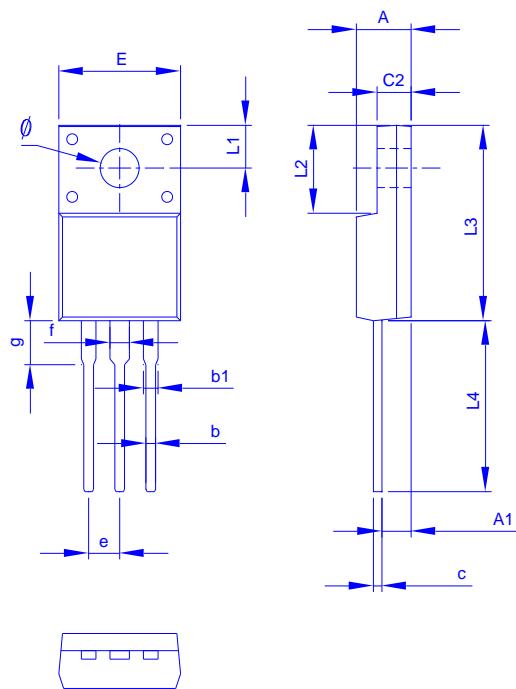
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMD26N10F for TO-220F



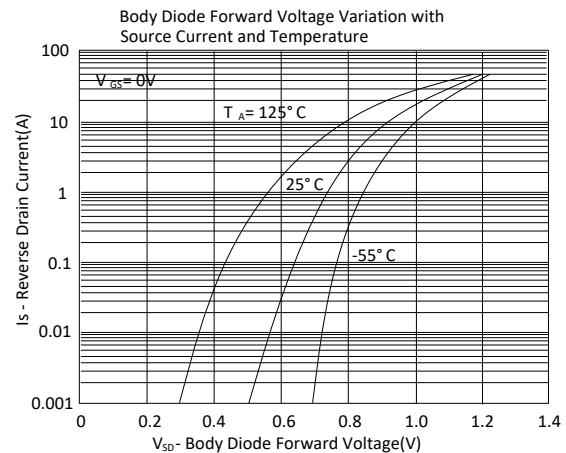
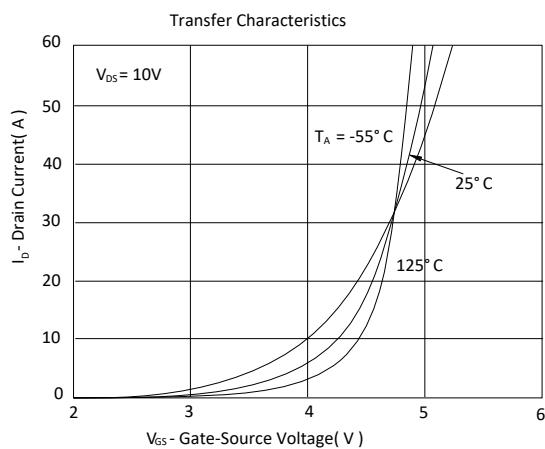
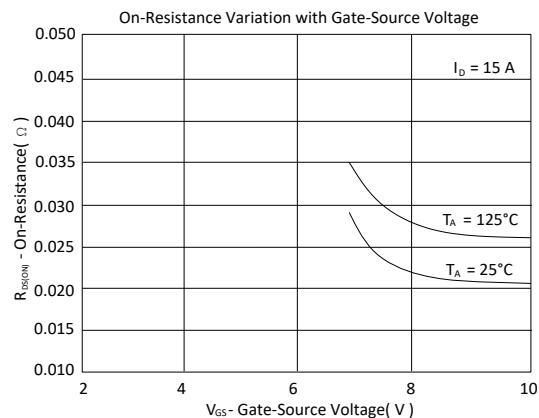
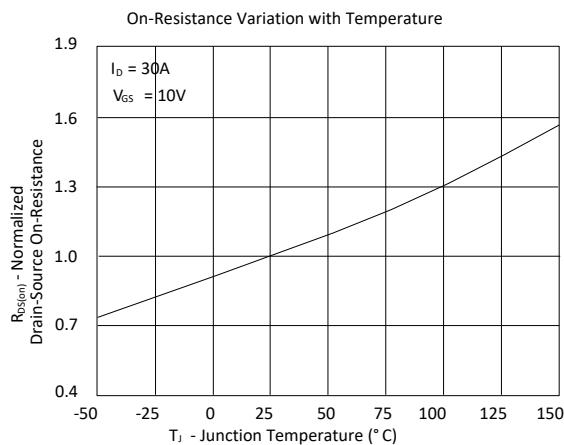
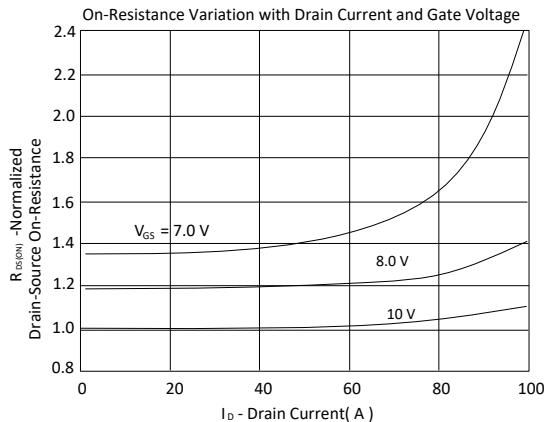
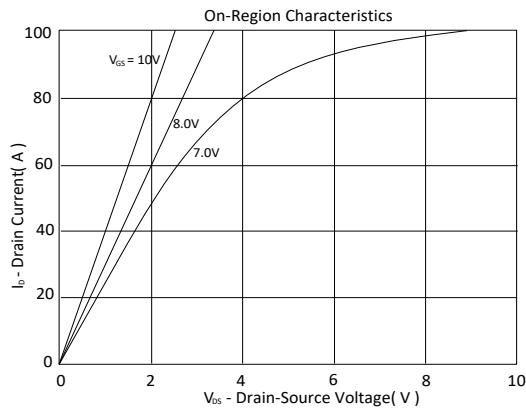
Outline Drawing

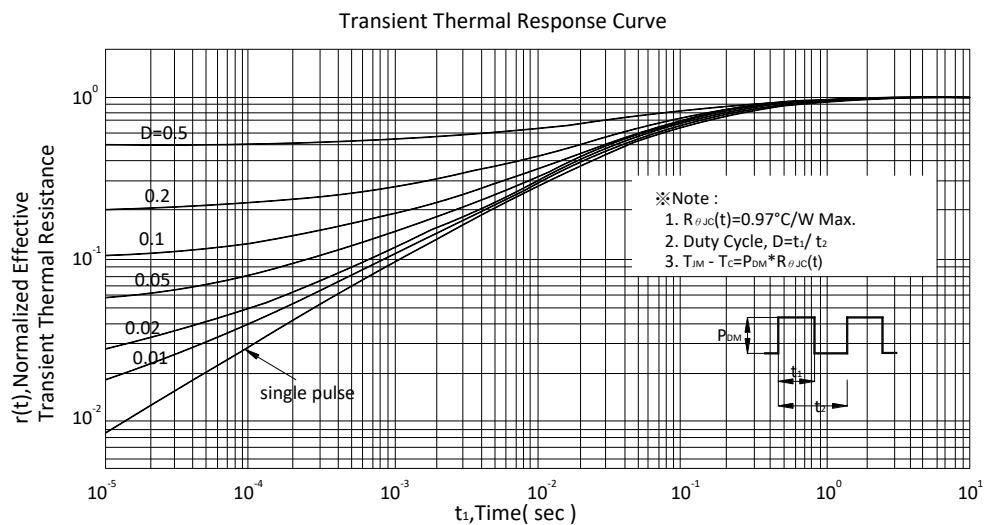
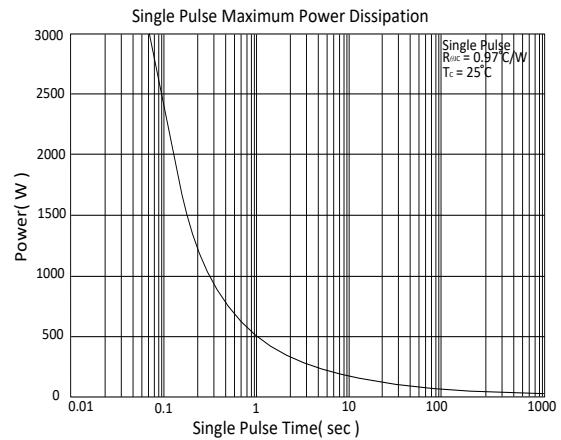
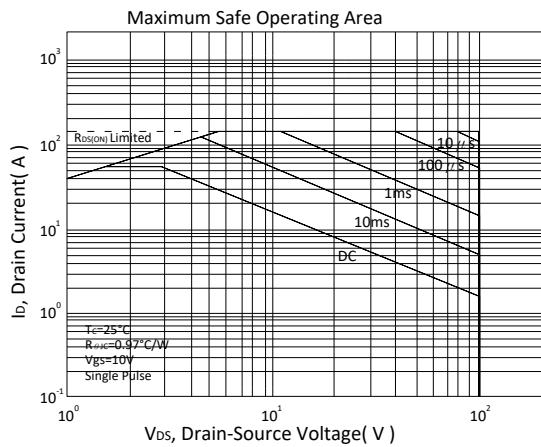
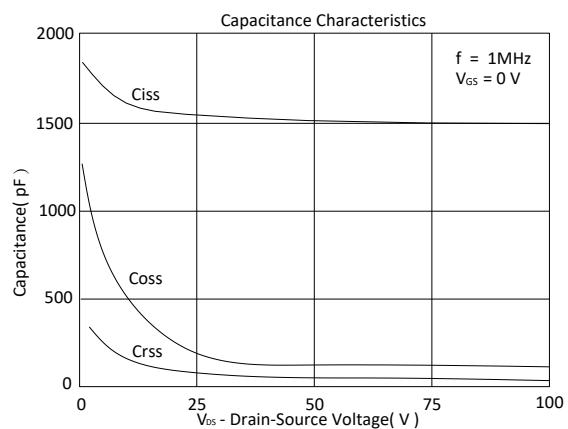
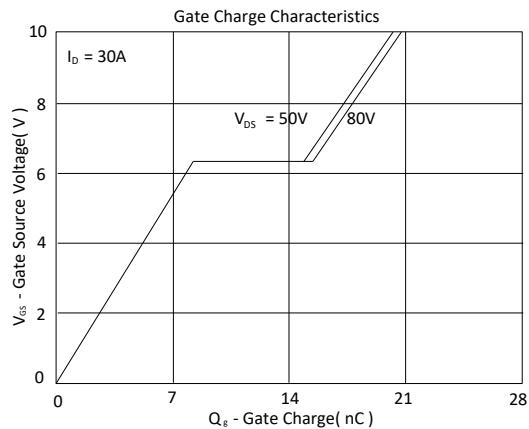


Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L1	L2	L3	L4	Ø	e	f	g
Min.	4.3	2.49	0.5	1.1	0.4	2.34	9.96	2.7	6.48	14.8	12.65	3	2.44	1.17	2.93
Typ.	4.5	2.59	0.8	1.3	0.5	2.54	10.1	3.25	6.68	15.87	12.98	3.1	2.54	1.28	3.03
Max.	4.9	2.96	0.95	1.6	0.75	3.2	10.36	3.45	6.9	16.2	13.5	3.38	2.64	1.75	4

TYPICAL CHARACTERISTICS





◆ Tube Information: 50pcs/Tube (1000pcs/Box)

